

**Search Notes**

Application/Control No.

10/538,632

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

OSMAN ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	107	11/1/2007	HN
330	310	11/1/2007	HN
330	98	11/1/2007	HN
330	133	11/1/2007	HN
330	150	11/1/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	10/28/2007	HN